REMARKS

Claims 1, 3, 5, 7-9, 11-13, 26-37 and 39-42 are pending in this application. By this Amendment, claims 1, 34 and 39 are amended, claim 38 is canceled without prejudice or disclaimer and new claims 40-42 are added. Various amendments are made to the claims for clarity and are unrelated to issues of patentability. Claims may be broader than specific examples discussed in the present specification.

Applicant respectfully submits that the April 5 Office Action is a non-final Office Action. Therefore, applicant respectfully submits that the statements on page 14 of the Office Action are incorrect. Applicant respectfully requests that Examiner Dong clarify that the outstanding Office Action is a non-final Office Action.

Applicant gratefully acknowledges the courtesies extended by Examiner Dong during the telephonic interview of July 27 with applicant's representative, Mr. Oren. The substance of the interview is incorporated in the following remarks. This document should serve as the "Substance of the Interview."

The Office Action objects to claim 38 under 37 C.F.R. §1.75. By this Amendment, dependent claim 38 is canceled. Thus, the objection is moot.

The Office Action rejects claims 1, 3, 5, 7-9 and 11 under 35 U.S.C. §103(a) over U.S. Patent 6,514,111 to Ebihara in view of U.S. Patent 5,972,564 to Kawana. The Office Action also rejects claims 12 and 13 under 35 U.S.C. §103(a) over Ebihara in view of Kawana and further in view of U.S. Patent 6,261,144 to Nishiki. Still further, the Office Action rejects claims 26-28, 30, 31, 38 and 39 under 35 U.S.C. §103(a) over U.S. Patent 6,495,262 to Igeta in view of Kawana.

Even further, the Office Action rejects claim 29 under 35 U.S.C. §103(a) over Igeta in view of Kawana and Ebihara. Still further, the Office Action rejects claims 32, 33 and 37 under 35 U.S.C. §103(a) over Ebihara. The rejections are respectfully traversed with respect to the pending claims.

Independent claim 1 recites at least one of a buffer layer or a dielectric layer formed between the first substrate and the sealing layer, wherein the at least one of the buffer layer or the dielectric layer has the following composition: PbO at a ratio of 45% to 55%, B_2O_3 at a ratio of 10% to 20% and SiO_2 at a ratio of 15%-25%.

As discussed during the telephonic interview, the applied references do not teach or suggest at least these features of independent claim 1. More specifically, the Office Action states that Ebihara does not specifically disclose the detailed composition of the claimed dielectric layer. The Office Action then relies on Kawana's col. 5, lines 23-25 for features relating to the claimed composition. However, Kawana relates to forming electrodes of a plasma display panel. The electrodes are formed using various features such as disclosed at col. 3, lines 32-43. These materials include a glass frit such as discussed at the cited col. 5, lines 26-33. Accordingly, the cited section relates to a glass frit of an electrode. This does not teach or suggest the claimed composition of at least one of a buffer layer or a dielectric layer formed between a first substrate and a sealing layer. Further, there is no suggestion to modify Ebihara's layer 24 based on composition of glass frit of Kawana's electrode. Accordingly, the Office Action's combination of Ebihara and Kawana does not teach or suggest all the features of independent claim 1. Thus, independent claim 1 defines patentable subject matter.

Independent claim 26 recites at least one of a buffer layer or a dielectric layer formed between the first substrate and the sealing layer, wherein the at least one of the buffer layer or the dielectric layer has a thermal expansion coefficient of approximately $72x10^{-7}/°C$ to $85x10^{-7}/°C$.

As discussed during the telephonic interview, the applied references do not teach or suggest at least these features of independent claim 26. The Office Action states that Igeta does not disclose that at least one of the buffer layer or the dielectric layer has a thermal expansion coefficient greater than or equal to $72x10^{-7}/°C$. The Office Action then cites Kawana's col. 5, lines 23-25 as being a same composition of the buffer layer or dielectric layer as the present application. The Office Action then states that because Kawana teaches a same composition, Kawana therefore exhibits the claimed thermal expansion coefficient.

However, for at least similar reasons as set forth above, Kawana does not teach or suggest the claimed buffer layer or dielectric layer as recited in independent claim 26. Rather, Kawana's composition at col. 5, lines 22-23 corresponds to glass frit of an electrode. This composition does not correspond to the composition of the buffer layer or the dielectric layer formed between a first substrate and a sealing layer. Therefore, the applied references do not teach or suggest a same composition of the claimed buffer layer or dielectric layer. Therefore, the applied references do not suggest the claimed thermal expansion coefficient as recited in independent claim 26. Further, there is no suggestion to modify Igeta's buffer layer 22b (FIG. 3) based on glass frit of Kawana's electrode. Accordingly, independent claim 26 defines patentable subject matter.

Independent claim 32 recites at least one of a buffer layer or a dielectric layer provided on the first substrate and provided between the first substrate and the sealing layer, wherein the buffer layer has a thickness of 35μm to 50 μm between the sealing layer and the first substrate.

The Office Action states that Ebihara's col. 4, lines 49-56 discloses a center portion of the dielectric layer 4 having a thickness of about 40μm for the purpose of permitting reduction of electrostatic capacity between display electrodes so that the power consumption for charging the electrostatic capacity upon later discharge becomes smaller and thus achieving a lower power consumption. However, the cited section of Ebihara corresponds to a center portion of the dielectric layer 4. The cited thickness does not relate to a thickness of the peripheral position 4a. See col. 9, lines 39-58 and FIG. 4. That is, Ebihara's peripheral area 4a is less than 35μm based on the explanation at col. 6, lines 5-11 and FIG. 4. Accordingly, the thickness discussed in the cited section of col. 4, lines 49-56 does not suggest at least one of a buffer layer or a dielectric layer provided between the first substrate and the sealing layer. Accordingly, Ebihara does not teach or suggest all the features of independent claim 32. Accordingly, independent claim 32 defines patentable subject matter.

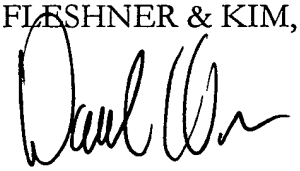
For at least the reasons set forth above, each of independent claims 1, 26 and 32 defines patentable subject matter. Each of the dependent claims depends from one of the independent claims and therefore defines patentable subject matter at least for this reason. In addition, the dependent claims recite features that further and independently distinguish over the applied references.

CONCLUSION

In view of the foregoing, it is respectfully submitted that the application is in condition for allowance. Favorable consideration and prompt allowance of claims 1, 3, 5, 7-9, 11-13, 26-37 and 39-42 are earnestly solicited. If the Examiner believes that any additional changes would place the application in better condition for allowance, the Examiner is invited to contact the undersigned attorney at the telephone number listed below.

To the extent necessary, a petition for an extension of time under 37 C.F.R. 1.136 is hereby made. Please charge any shortage in fees due in connection with the filing of this, concurrent and future replies, including extension of time fees, to Deposit Account 16-0607 and please credit any excess fees to such deposit account.

Respectfully submitted,
FLESHNER & KIM, LLP



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